

*Loresta-GX II* MCP-T710

Accurate resistivity measurement using the reliable  
4-pin probe method

# *Loresta-GX II*

Low resistivity meter, Measuring range  $10^{-4} \sim 10^7 \Omega$

Expanded Measuring Range and Useful Functions  
Functional 7.5-inch color LCD Touch-Screen



- Expanded measuring range,  $10^{-4} \sim 10^7 \Omega$
- Silicon Mode for silicon wafer measurement
- One-touch automatic measurement by new functions, Auto-hold and Timer Mode
- Real-time output of measurement results

#### Standard accessories



ASR Probe  
RMH501



ASR Probe checker  
RMH304

\*Probes for Loresta GX cannot be connected to Loresta GXII

**Nittoseiko Analytech Co., Ltd.**

# Loresta-GX II

(MCP-T710)

- Accurate Low Resistivity Meter based on 4 Terminal 4 Pin Method
- One-touch measurement by dedicated probe on  $\Omega$ ,  $\Omega/\square$ ,  $\Omega\cdot\text{cm}$  and  $S/\text{cm}$
- Operation on Touch-Screen, RCF setting, Measurement, Data Save, Data Output and Data Management

Accurate and quick measurement of materials' resistivity

## 4 Terminal 4 Pin Method

- High accuracy with eliminating contact resistance between sample and probe and lead wire's resistance
- Dedicated probe with spring contact method keeps constant pin pitch, pressure and contact area on samples



● Probe should be placed perpendicularly on samples.

### Uses

## ■ Production engineering ■ Quality control ■ R & D

### Applications

- Conductive paint, Conductive ink, Conductive paste, Resistive paste (carbon etc.), Conductive plastics, Conductive rubber, Silicon wafer
- Conductive films, Transparent conductive films, ITO Glass, Metal evaporated films, Sprayed metal layers, Sheet metals, Antistatic materials, Electromagnetic shield materials, Conductive fiber, Conductive ceramics, etc.
- Plating, Magnesium alloy, Surface treatment, etc.

### Features

- Expanded measuring range:  $0.001 \times 10^{-4} \sim 9.999 \times 10^7 \Omega$
- One-touch operation: Automatic measurement with functional Auto-hold and Timer Mode
- Silicon Mode for silicon wafer measurement
- Low conductive materials are acceptable by Selectable Applied Current Function
- Current polarity reversing makes stable measurement
- Real-time output of measurement results to a PC (using data logger software sold separately)

### Specifications

- Method: 4 Terminal 4 Pin Method
- Measurement mode: Auto-hold
- Mode: Measurement end by value's stability.
- Timer Mode: Measurement end by set time
- Display: 640x480dots, 7.5 inch full-color TFT-LCD touch screen
- Data output: USB flash drive, Serial (USB B)
- Power source: AC85~264V 47~63Hz, 40VA
- Dimensions, weight: W320 x D285 x H110mm, Lid opened H200mm, approx. 2.4kg
- Standard accessory: ASR probe RMH501 and Probe checker RMH304

\*Specifications and appearance are subject to change without prior notice.



● Check the probe with Probe Checker prior to measurement.

		Supply current							
		1A	100mA	10mA	1mA	100 $\mu$ A	10 $\mu$ A	1 $\mu$ A	0.1 $\mu$ A
Range	10 <sup>-4</sup>	$\pm (2.0\% + 30\text{dgt})$							
	10 <sup>-3</sup>	$\pm (2.0\% + 20\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$						
	10 <sup>-2</sup>	$\pm (1.0\% + 5\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$					
	10 <sup>-1</sup>	$\pm (1.0\% + 3\text{dgt})$	$\pm (1.0\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$				
	10 <sup>0</sup>		$\pm (0.5\% + 3\text{dgt})$	$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$			
	10 <sup>1</sup>			$\pm (0.5\% + 3\text{dgt})$	$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$		
	10 <sup>2</sup>				$\pm (0.5\% + 3\text{dgt})$	$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$	
	10 <sup>3</sup>					$\pm (0.5\% + 3\text{dgt})$	$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$	$\pm (2.0\% + 20\text{dgt})$
	10 <sup>4</sup>						$\pm (0.5\% + 3\text{dgt})$	$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 5\text{dgt})$
	10 <sup>5</sup>							$\pm (0.5\% + 3\text{dgt})$	$\pm (1.0\% + 3\text{dgt})$
10 <sup>6</sup>								$\pm (1.0\% + 3\text{dgt})$	
10 <sup>7</sup>								$\pm (2.0\% + 5\text{dgt})$	

### Options

\* Probes for Loresta GX cannot be connected to Loresta GXII

● ESR



**RMH502**

For non-uniform samples  
Pin pitch 5mm  
Pin point's diameter 2mm x 4pins  
Spring pressure 230g/pin

● LSR



**RMH503**

For soft surface samples  
Pin pitch 5mm  
Pin top hemisphere 2mm x 4pins  
Spring pressure 140g/pin

● PSR



**RMH504**

For small samples  
Pin pitch 1.5mm  
Pin points 0.26R x 4pins  
Spring pressure 95g/pin

● QR



**RMH505**

For very small samples  
Pin pitch 1.5mm  
Pin points 0.26R x 4pins  
Pin arrangement Square  
Spring pressure 95g/pin

● BSR



**RMH506**

For very large samples  
Pin pitch 2.5mm  
Pin points 0.37R x 4pins  
Spring pressure 170g/pin

● NSCR



**RMH507**

For Silicon Wafer  
Pin pitch 1.0mm  
Pin points 0.04R x 4pins  
Spring pressure 250g/pin

### Note:

Follow instructions in manuals to correctly install, connect and operate the instruments. Contents of catalogues are subject to change without prior notice when improvements are made in performance. The actual color of the goods may appear different from color printed. All screen images are simulated.

\*Company and product names contained herein are the trademarks or registered trademarks of the company concerned.

## Nittoseiko Analytech Co., Ltd.

7-10-1 Chuo-rinkan, Yamato, Kanagawa 242-0007, JAPAN

Tel: +81(0)46-278-0056

URL: <https://www.n-analytech.co.jp/global>

CAT No.29080223081E